



Mar. 03, 2017

No: WD-EE-L-170031-00

Congratulation! Wendell Electrical Test Laboratory declare that the below representative model(s) for your product(s) has been evaluated and determined to comply with the required criteria levels in the Standard(s).

The test record, data evaluation, EUT configurations, measured procedures of specified in the standard as indicated in test report (No: WD-EE-R-170031-00). The test data evaluation in the test report relate only to the EUT sample(s) and test item(s).

**Equipment:** HMI (Human Machine Interface)

Model Name: MT8071iP, MT6071iP

**Brand Name:** Weintek, EasyView, Weinview

**Applicant:** Weintek Labs., Inc.

Address: 3F, No. 910, Zhongzheng Rd., Zhonghe Dist., New Taipei City, Taiwan

Standard(s): EMC Directive of 2014/30/EU

EN 55032: 2012 +AC: 2013, Class A

CISPR 32: 2012

Mick Lm.

Nick Lin / Authorized Signatory

Wendell Industrial Co., Ltd
Wendell Electronic Test Laboratory







Jun. 20, 2016

No: WD-EE-L-160095-00

Congratulation! Wendell Electrical Test Laboratory declare that the below representative model(s) for your product(s) has been evaluated and determined to comply with the required criteria levels in the Standard(s).

The test record, data evaluation, EUT configurations, measured procedures of specified in the standard as indicated in test report (No: WD-EE-R-160095-00). The test data evaluation in the test report relate only to the EUT sample(s) and test item(s).

**Equipment:** HMI (Human Machine Interface)

Model Name: MT8071iP, MT6071iP

**Brand Name:** Weintek, EasyView, Weinview

**Applicant:** Weintek Labs., Inc.

Address: 3F, No. 910, Zhongzheng Rd., Zhonghe Dist., New Taipei City, Taiwan

Standard(s): EMC Directive of 2014/30/EU

EN 55022: 2010 +AC: 2011, Class A

CISPR 22: 2008 (Ed 6.0) EN 61000-3-2: 2014 EN 61000-3-3: 2013 EN 55024: 2010 IEC 61000-4-2: 2008 IEC 61000-4-3: 2010 IEC 61000-4-5: 2014 IEC 61000-4-6: 2013 IEC 61000-4-8: 2009

IEC 61000-4-11: 2004

Cooper Lee / Authorized Signatory

## Wendell Industrial Co., Ltd Wendell Electronic Test Laboratory

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